Abstracts

An Improved Model for Noise Characterization of Microwave GaAs FET's

R.K. Froelich. "An Improved Model for Noise Characterization of Microwave GaAs FET's." 1990 Transactions on Microwave Theory and Techniques 38.6 (Jun. 1990 [T-MTT]): 703-706.

A simple, lumped-element noise model for microwave FET's is proposed where determination of the elements requires a minimal quantity of measured data. At the same time, the model is complete enough to yield good predictions of measured results. These predictions are in better agreement with measurements than those of a similar, recently published model.

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